

## **BRIDG Overview**

John J. Callahan, PhD Vice President of Technology

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RIDG Proprietary – BD 57/2019.6.04 – DOES NOT CONTAIN EAR TECHNOLOGY OR ITAR CONTROLLED TECHNICAL DATA





### Nano-Electronics Fabrication Facility: Cleanrooms and Labs Located within a new 500-acre high-technology campus in Osceola County, FL



## **Our Purpose**

#### Purpose:

BRIDG's community purpose is to create a more financially sound and diverse economy in Central Florida by serving as a catalyst for creating high wage job opportunities for residents and the broader Southeast region of United States.

As a not-for-profit, publicprivate partnership, and as good stewards of our region's infrastructure investment, our single largest metric of success is the creation of high wage jobs in the region.





## **Approximately \$300M Invested to Date**

## NECCITY

*"Florida grown" infrastructure investment with roots deeply embedded in the region and state.* 

#### **Founding Visionaries**







## **Trust and Facility Clearance**

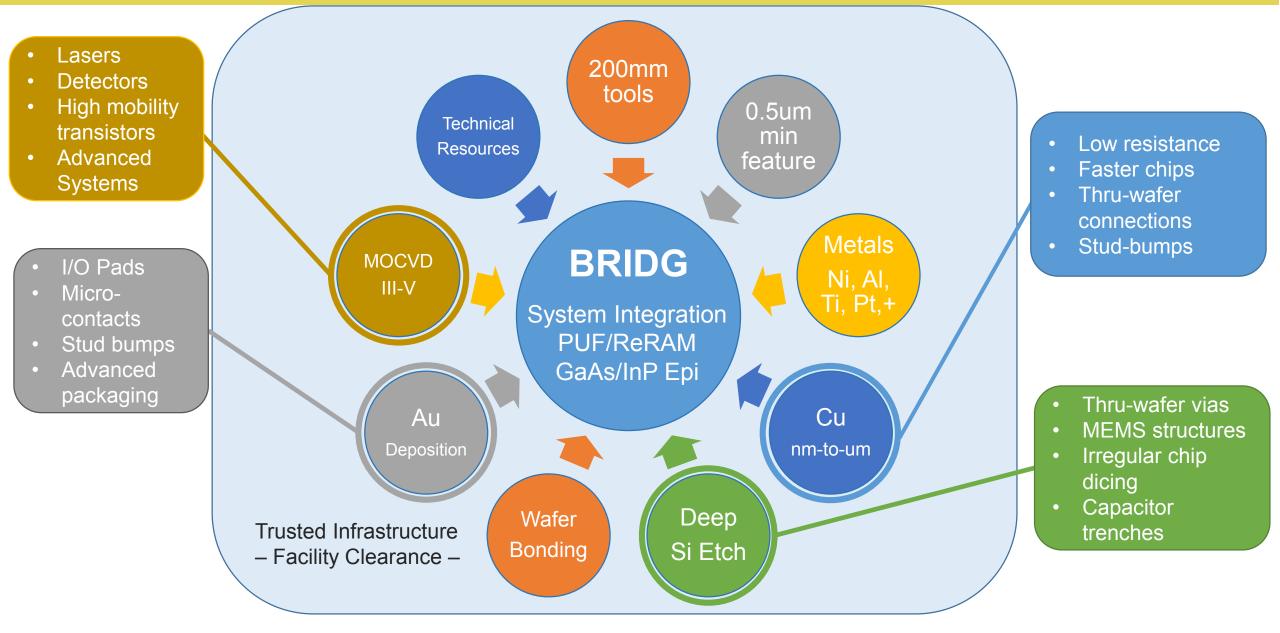
### + BRIDG is "Trust Ready"

- Heading towards DMEA Trusted Supplier Accreditation
- + DSS Facility Clearance at SECRET level
  - Received July 2018
- + ITAR Qualified
  - Fab, Lab, Office and IT infrastructures
- + BRIDG has been sponsored by AT Program Office to become a cleared facility early 2018





## **Near Term Capabilities**





## **Tool Installation Completed End of June'18**







## **Current and Future Tool Set**

#### **Existing Tools**

#### Future Tools

Lithography
Stepper –Nikon i-Line i12
Coater / Developer – TEL ACT8
Deposition
CVD HDP – AMAT Centura
CVD – AMAT Centura (W)
CVD – Novellus C2 Sequel (SiN, SiO2)
PVD – AMAT Endura (Cu, TaN, Al, TiN, RPC)
Evaporator – Temescal UEFC-4900 (Au, Pt, Ti, Al, Ni, etc.)
Furnaces – Tel Alpha 8s (Oxide, Nitride, Poly, Diffusion)
Anneal
Furnaces – Tel Alpha 8s Anneal
RTA – SSI Solaris
Etch
Etch AMAT CENTURA (Metal Etch)
<b>Etch</b> AMAT CENTURA (Metal Etch) AMAT CENTURA (Oxide Etch)
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Box Washer – Flouroware HTC-810	

CMP – AMAT Mirra Trak (Cu) CMP – AMAT Mirra Trak (Oxide/W) Implant Ion Implant – Varian E500 (Medium Current) Wafer Bonding / Die Bonding Bond Aligner / Mask Aligner – SUSS MABA8 Bond Alignment Metrology – SUSS DSM8/200 Gen2 Bonder, Permanent – SUSS XB8 Print Transfer – Xceleprint Metrology / Inspection/Test CD SEM – SEM5 Hitachi 9320 XRD, XRR, XRT – Panalytical X'PERT3MRD Defect Inspection – KLA 2139 - Bright Field Ellipsometer, Stress Measure – KLA F5x Goniometer – Rame-Hart Defect Measure – KLA Candela CS920 Profiler – KLA P-170 Digital Microscope - Keyence Overlay – Inspectrology 4-Point Probe – CDE SEM-FIB-EDX FormFactor Summit 200 Prober Epi Growth III/V MOCVD – Veeco D180 Hall and PL Systems	
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Hall and PL Systems	III/V MOCVD – Veeco D180
	Hall and PL Systems

#### Partner Demo Labs

#### **Demo Lab**

#### ALD Oxide

Dismount solvent cleaner Wafer De-bonder, Mechanical Wafer De-bonder, Laser High Accuracy Wafer Bonder <100nm Ancillary Material Track Nano-imprint Spray Coater

Processing
Plating system Ni, Au, SAC, SnAg
Polymer Curing Oven
Solder ball deposition
Wafer thinning tool
Dicing saw & mounting
Edge Grinder
ALD metal

#### **Test & Reliability**

**RF** Test Equipment

Reliability / Stress ovens

Lithography

Direct Write Photolithography

Fine Line Lithography

ebeam

#### Assembly High Accuracy Die Bonder

Metrology	
	Sonoscan
	Surfscan
	XRF/VPD
	CV Measurement
	ТЕМ

Operational
Planning in process
Not installed

ISERT APPROVED ID (I.C. BD 001/2018.02.06) — DOES NOT CONTAIN EAR TECHNOLOGY OR ITAR CONTROLLED TECHNICAL DATA

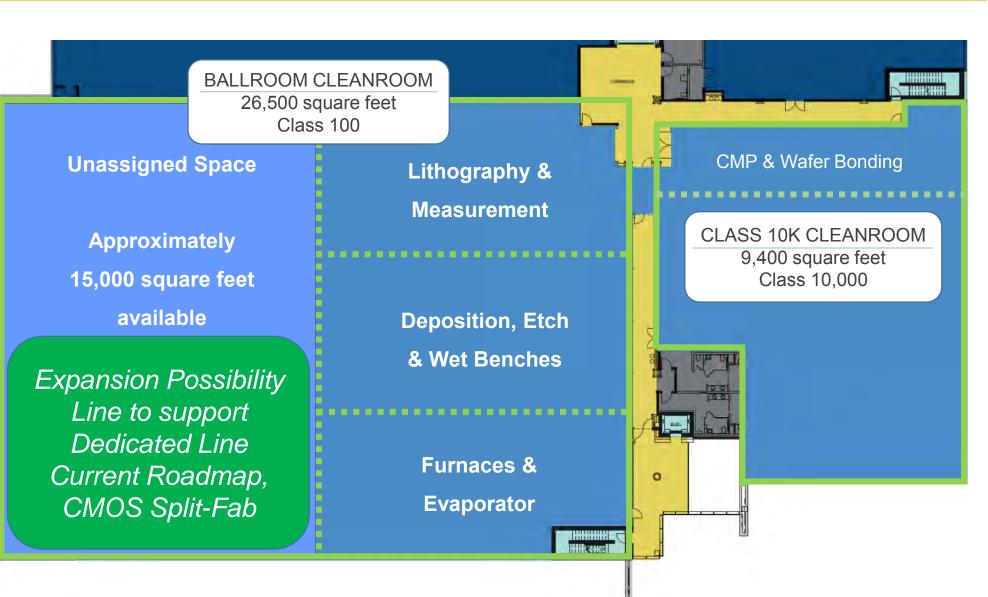


## **Cleanroom Opportunities for Partners**

Leverage \$239M+ in Local Investment

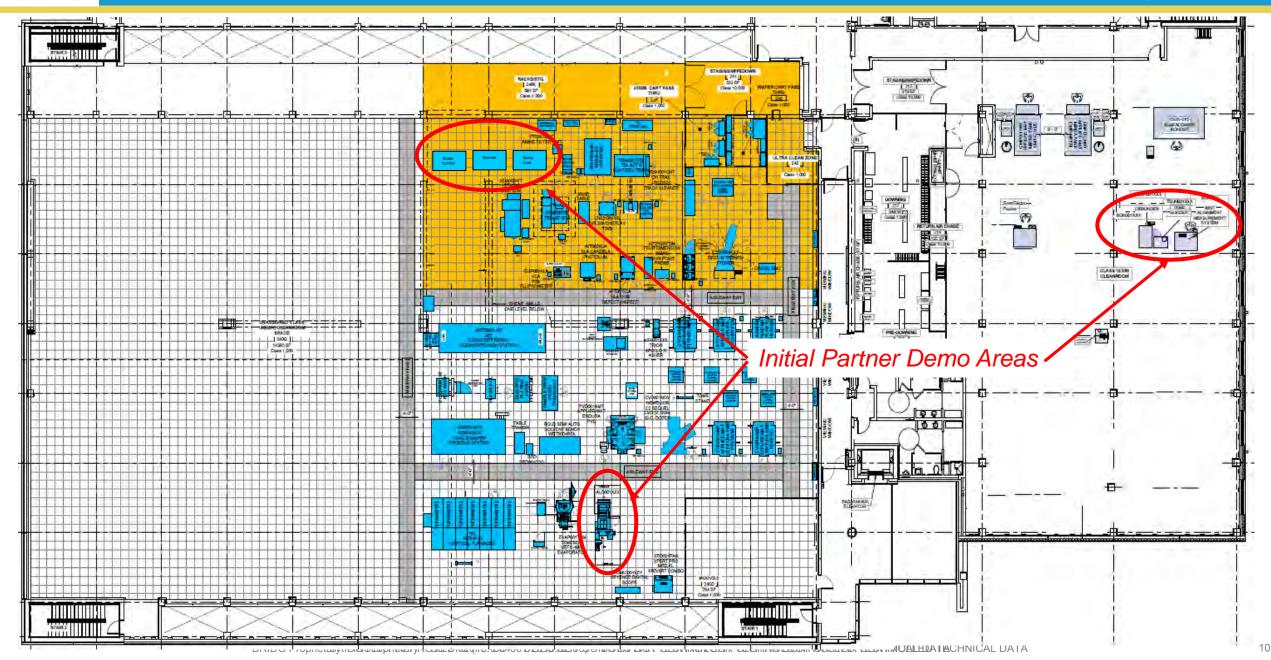
Building can be incrementally expanded or fully mirrored along this axis

- Permitting Complete
- Support Infrastructure Built for this Expansion
- \$80M for Full Mirroring
- 1 year start-to-finish



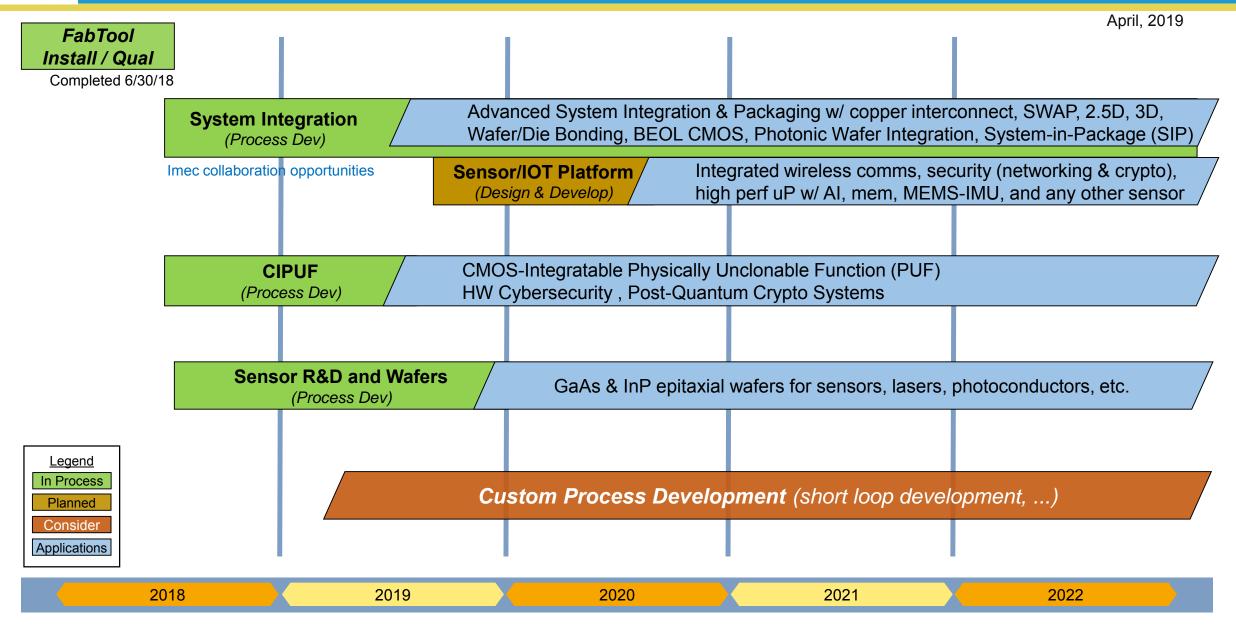


## **Class 100 and 10K Floorplans**



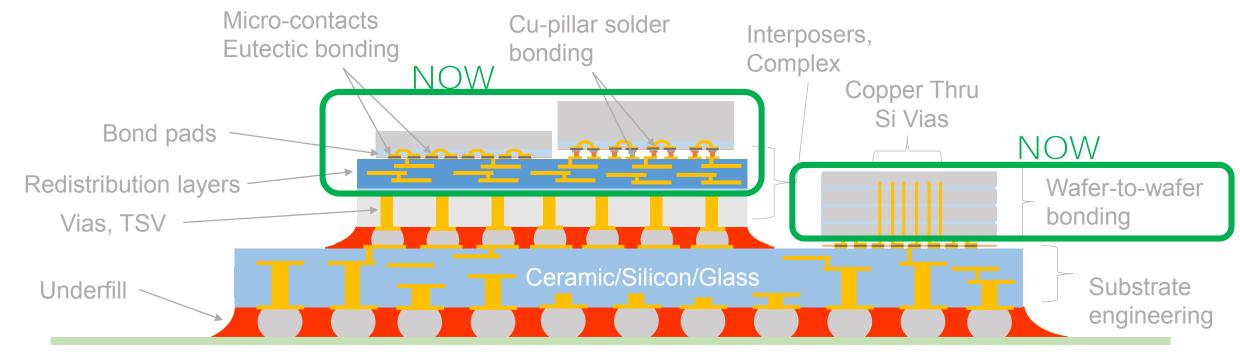


## **BRIDG Technology Roadmap**





#### Providing solutions for size, weight and power reduction to address challenges faced by conventional scaling



### Improved performance

- Heterogeneous Integration (Si, III/V, Photonics)
- Ultra-High Density (Wide I/O 10<sup>6</sup>)
- Power Consumption and System Response Time
- Robust Operating Temperature Range (77K to 673K)

#### **Improved Form Factor**

Transform traditional sensing techniques allowing continuous monitoring and the ability to monitor more...

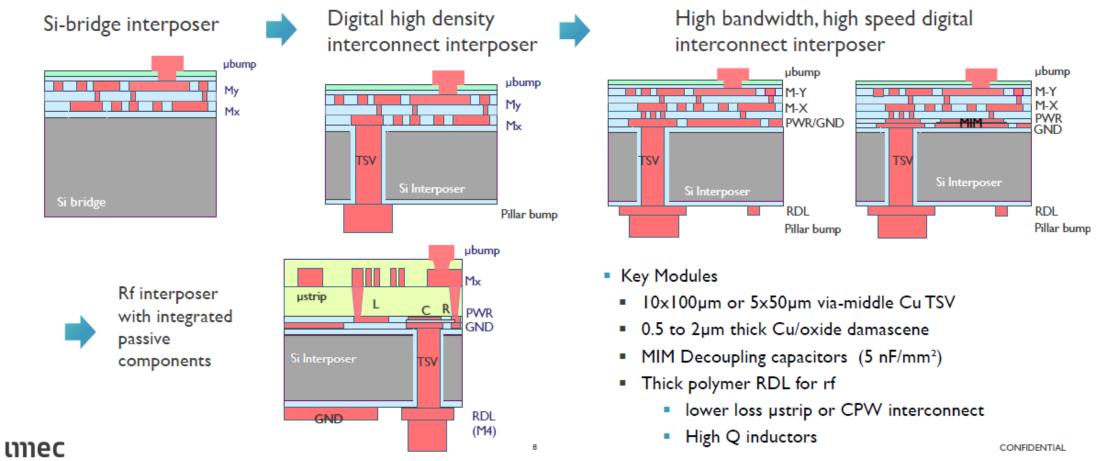
Enabling System Miniaturization



### FLEXIBLE SI INTERPOSER TECHNOLOGY

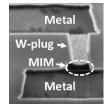
### FOR HIGH DENSITY INTEGRATION OF RF AND MIXED ANALOG/DIGITAL MSYSTEMS

Modular approach, topology by application requirements

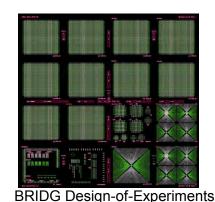


# **ReRAM-PUF Technology– BRIDG Differentiators**

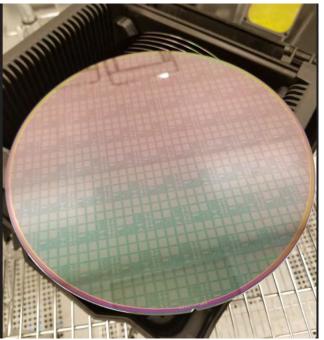
- + CMOS compatible Physically Unclonable Function (PUF)
  - Newly discovered (Feb'17) PUF capability leaves no trace or residue in hardware extremely hard to discover
- + Applications: Secure the IOT, validate payment systems, ensure safe connectivity, smartcards, authenticate sensors, and protect sensitive military data and systems



- + Significance: provides a root-of-trust for multiple layers of security that is
  - Extremely **low power** (femto-Joules to read)
  - Highly integrate-able into any computer system, ASIC, SoC and FPGA
  - Exceptionally difficult to hack; non-detectable element
  - Very high source of entropy with stability, reliability and performance
  - Provides Anti-Tamper protection against cloning, counterfeiting, overbuilding, reverse engineering and data leakage
  - Key storage, key management and crypto functionality
  - Radiation hardened
  - Requires specific methodology for using it



Mask Design



BRIDG ReRAM-PUF Wafer



## **Sensor R&D and Wafers**

BRIDG offers MOCVD growth of GaAs, InP and GaSb based III-V binary, ternary and quaternary epitaxial structures for the fabrication of high performance electronic and optoelectronic devices with high yield.

#### MOCVD

#### System

- > High throughput multiple wafer system
- ➢ Wafer size: 2"- 6"
- In-situ control systems to grow high thickness/composition uniformity structures (<1%) and doping control</li>

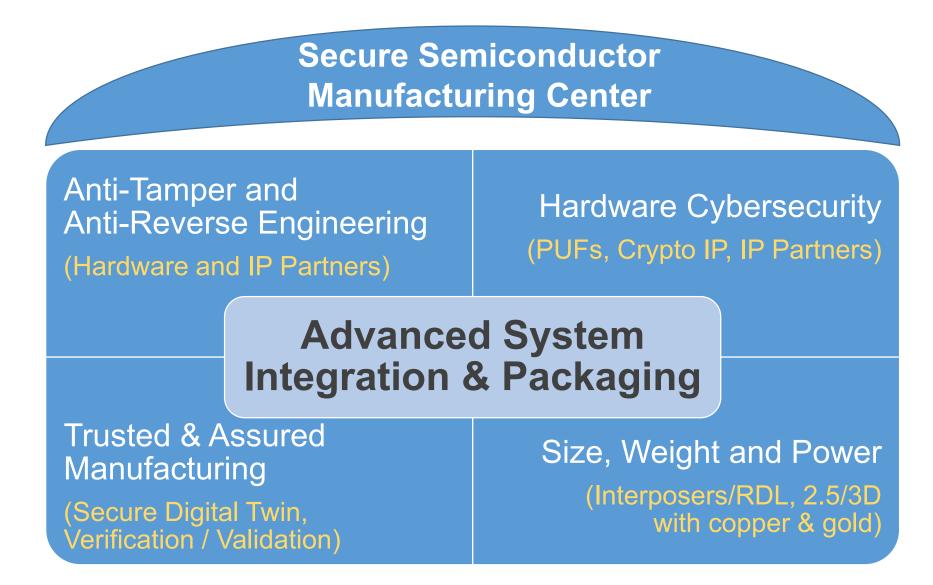
### Applications

- Light Emitting Diodes (LED)
- Edge Emitting Lasers
- Photodetectors
- Sensors and Detectors
- Solar Cells
- > HFETs/HEMTs/HBTs/Gunn Diodes





## **Secure Semiconductor Manufacturing Concepts**





# Momentum!!



# Join Us

magnetizing a global economy to thrive within a place conceived through an ethos of collaboration

powering the innovation and development of technologies we can't even imagine yet Join us in the next evolution of innovation!

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GoBRIDG.com